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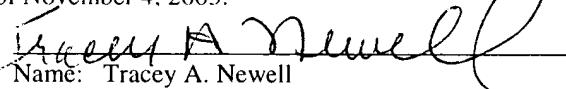
2815

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of :  
Yoshitaka YOKOYAMA :  
:  
:  
:  
Appln. No.: 09/804,499 : Art Unit: 2815  
:  
Filed: March 12, 2001 : Examiner: NGUYEN, Joseph H.  
:  
For: **WAVELENGTH STABILIZED LASER** : Docket No.: NIM-01301  
**MODULE** :  
:

**Certificate of Mailing**

I hereby certify that the foregoing documents are being deposited with the United States Postal Service as first class mail, postage prepaid, in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on this date of November 4, 2003.

  
Name: Tracey A. Newell

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Submitted herewith on Form PTO-1449 is a listing of documents known to Applicants and/or their attorney in compliance with the requirements of 37 C.F.R. 1.56. Copies of the documents are also being submitted.

The references submitted herewith were cited by the European Patent Office in a September 26, 2003 Search Report (copy enclosed) for a counterpart application. Since this Information Disclosure Statement is being filed within three months of that date, and prior to either a Final Office Action or a Notice of Allowance for this case, no fee is due. The relevance of non-English language references is set forth in the Search Report. In addition, we enclose English language abstracts for references AO and AP, listed on the attached Form 1449.

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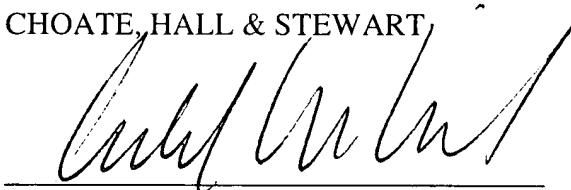
The Examiner is respectfully requested to initial the space adjacent to each document on the PTO-1449 form and return a copy of the PTO-1449 form to confirm that these documents have been considered by the Examiner and made of record in this application.

Although we believe that we have appropriately provided for any fees due in connection with this submission, the Commissioner is authorized to credit any overpayment or charge any deficiencies to/from our **Deposit Account No. 031721**. Two originally-executed copies of this form are being submitted.

Should there be any questions after reviewing this paper, the Examiner is invited to contact the undersigned at (617) 248-4038.

Respectfully submitted,

CHOATE, HALL & STEWART

  
Donald W. Muirhead  
Registration No. 33,978

November 4, 2003

Date

Patent Group  
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Exchange Place  
53 State Street  
Boston, Massachusetts 02109

INFORMATION DISCLOSURE CITATION <i>IN AN APPLICATION</i> <i>(Use several sheets if necessary)</i>		Docket Number (Optional) NIM-01301	Application No. 09/804,499
NOV 9 6 2003		Applicant Yoshitaka YOKOYAMA	
		Filing Date March 12, 2001	Group Art Unit 2815

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	5,760,419	06/02/1998	Rashit F. Nabiev, et al.			
AB	5,216,237	06/01/1993	Simon Ritchie, et al.			
AC	4,821,273	04/11/1989	Nobuo Hori			
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## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
AL	EP 0 390 525 A2	10/03/1990	EPO				
AM	EP 0 818 857 A1	01/14/1998	EPO				
AN	PCT/US98/25142	11/24/1998	PCT				
AO	58 056539 A	04/04/1983	Japan			(English Abstract)	R
AP	2000 56185 A	02/25/2000	Japan			(English Abstract)	R
AQ							

## OTHER DOCUMENTS

(Including author, Title, Date, Pertinent Pages)

AR	T. Nieml, et al.: "Temperature-Tunable Silicon-Wafer Etalon for Frequency Chirp Measurements", Microwave and Optical Technology Letters, John Wiley & Sons, Inc., NY, NY, US, vol. 20, no. 3, February 5, 1999, pages 190-192; ISSN: 0895-2477/99
AS	
AT	
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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.